

**Notice of References Cited**

Application/Control No.

09/930,856

Applicant(s)/Patent Under  
Reexamination  
CHEN ET AL

Examiner

DuyVu n Deo

Art Unit

1765

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,492,214	12-2002	Chen et al.	438/183
	B	US-6,080,639	06-2000	Huang et al.	438/435
	C	US-5,968,610	10-1999	Liu et al.	427/579
	D	US-5,814,564	09-1998	Yao et al.	438/723
	E	US-5,637,896	06-1997	Huang	257/316
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable, Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	X	

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